

United States Patent and Trademark Office

UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO	. 1	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/676,411	11 09/30/2003		Robert Bristol	42P16691	8060
8791	7590	09/13/2006	EXAMINER		
		LOFF TAYLOR &	CHACKO DAVIS, DABORAH		
12400 WILSHIRE BOULEVARD SEVENTH FLOOR				ART UNIT	PAPER NUMBER
LOS ANG	LOS ANGELES, CA 90025-1030			1756	
				DATE MAILED: 09/13/2000	5

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)					
	10/676,411	BRISTOL ET AL.					
Office Action Summary	Examiner	Art Unit					
	Daborah Chacko-Davis	1756					
The MAILING DATE of this communication appears on the cover sheet with the correspondence address Period for Reply							
A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION. - Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication. - Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).							
Status							
 1) Responsive to communication(s) filed on 28 Ju 2a) This action is FINAL. 2b) This 3) Since this application is in condition for allowant closed in accordance with the practice under Extended 	action is non-final. ace except for formal matters, pro						
Disposition of Claims							
4) ☐ Claim(s) 1-24 is/are pending in the application. 4a) Of the above claim(s) is/are withdraw 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-24 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/or							
Application Papers							
9) ☐ The specification is objected to by the Examiner. 10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner. Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a). Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d). 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.							
Priority under 35 U.S.C. § 119							
 12) Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f). a) All b) Some * c) None of: 1. Certified copies of the priority documents have been received. 2. Certified copies of the priority documents have been received in Application No 3. Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)). * See the attached detailed Office action for a list of the certified copies not received. 							
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary (Paper No(s)/Mail Da 5) Notice of Informal Pa 6) Other:	te					

Art Unit: 1756

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claims 1-3, 7-11, 15-19, and 23-24, are rejected under 35 U.S.C. 102(b) as being anticipated by U. S. Patent No. 5,565,304 (Honda).

Honda, in col 3, lines 40-59, in col 4, lines 28-30, in col 5, lines 34-46, in col 8, lines 10-20, and lines 45-52, discloses a method of forming a pattern in a semiconductor device including forming a resist layer on a device layer (etch-resistant layer), said resist layer includes a baseline material such as polyhydroxystyrene, highly absorbing material such as antimony, thinning the resist material coating to a desired thickness, and improving the efficiency of the PAG in the resist to capture the secondary electrons produced in the resist (when exposed to X-ray, the radiation generates secondary electrons in the resist, resulting in the interaction of the PAG to produce a halogen acid (PAG in the resist is triphenyl sulfonium tetrafluoroborate) that catalyses the crosslinking reactions, thereby increasing the efficiency of the PAG, and controlling the moieties generated due to irradiation (proximal to the PAG), pattern transferring the resist pattern formed to define areas of the device (claims 1-2, 7, 9-10, 15, 17-18, and 23). Honda, in col 5, lines 40-46, and in col 6, lines 53-55, discloses that the antimony is added in the claimed amount (5% to 30%) in the resist composition (claims 3, 11, and

Art Unit: 1756

19). Honda, in col 8, lines 53-55, discloses that the resist layer is exposed to X-ray irradiation (claims 8, 16, and 24).

Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 4, 12, and 20, are rejected under 35 U.S.C. 103(a) as being unpatentable over U. S. Patent No. 5,565,304 (Honda) in view of U. S. Patent No. 6,753,129 (Livesay et al., hereinafter referred to as Livesay).

Honda is discussed in paragraph no. 2.

The difference between the claims and Honda is that Honda does not disclose the highly absorbing materials (claimed polymers) recited in claims 4, 12, and 20.

Livesay, in col 8, lines 45-58, discloses that the resist composition includes a fluoropolymer.

Therefore, it would be obvious to a skilled artisan to modify Honda by employing the absorbing material suggested by Livesay because Livesay, in col 5, lines 55-61, in col 7, lines 60-67, and in col 8, lines 20-57, discloses that adding fluoro polymers in resist compositions enables the formation of a uniform film on the substrate, and increases the surface hardness and dry etch resistance of the resist pattern.

Application/Control Number: 10/676,411

Art Unit: 1756

5. Claims 5, 13, and 21, are rejected under 35 U.S.C. 103(a) as being unpatentable over U. S. Patent No. 5,565,304 (Honda) in view of U. S. Patent No. 7,049,044 (Gonsalves et al., hereinafter referred to as Gonsalves).

Honda is discussed in paragraph no. 2.

The difference between the claims and Honda is that Honda does not disclose that the resist layer is thinned to a thickness below 100nm (claims 5, 13, and 21).

Gonsalves, in col 14, lines 25-34, discloses forming a thin layer of resist with a thickness less than 100nm.

Therefore, it would be obvious to a skilled artisan to modify Honda by employing the thickness range suggested by Gonsalves because Honda, in col 8, lines 10-21, discloses thinning the resist layer to a desired thickness and Gonsalves, in col 2, lines 1-25, teaches using the resist layer compositions to form sub-100nm patterning inorder to be applicable for next generation lithography.

6. Claims 6, 14, and 22, are rejected under 35 U.S.C. 103(a) as being unpatentable over U. S. Patent No. 5,565,304 (Honda) in view of U. S. Patent No. 5,034,304 (Feely). Honda is discussed in paragraph no. 2.

The difference between the claims and Honda is that Honda does not disclose increasing the PAG (photoacid generator) concentration in the resist (claims 6, 14, and 22).

Feely, in col 6, lines 15-35, discloses increasing the PAG concentration in the resist composition.

Application/Control Number: 10/676,411

Art Unit: 1756

Therefore, it would be obvious to a skilled artisan to modify Honda by increasing the concentration of the PAG in the resist as suggested by Feely because Feely, in col 6, lines 15-35, discloses using higher concentrations of PAG in the resist enables the resist to be imageable in X-ray wavelengths, and enables the formation of a much higher image resolution.

The state of the s

Response to Arguments

7. Applicant's arguments, filed June 28, 2006, with respect to claims 1-24, have been considered but are moot in view of the new ground(s) of rejection.

Conclusion

8. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Daborah Chacko-Davis whose telephone number is (571) 272-1380. The examiner can normally be reached on M-F 9:30 - 6:00. If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Mark F Huff can be reached on (571) 272-1385. The fax phone number for the organization where this application or proceeding is assigned is (571) 273-8300. Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you

Application/Control Number: 10/676,411

Art Unit: 1756

Page 6

have questions on access to the Private PAIR system, contact the Electronic Business

Center (EBC) at 866-217-9197 (toll-free).

dcd

September 8, 2006.

JOHN A. MCPHERSON PRIMARY EXAMINER